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LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.	APPLN. SERIAL NO.
P-0586	10/733,569
APPLICANT(S)	
Choong-Jae LEE	
FILING DATE	GROUP
December 12, 2003	2618

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
AH	5,804,780	9/1998	BARTHA, Istvan			
AH	6,148,080	11/2000	COLLIN, Pascal			
AH	6,904,300	6/2005	MAATTANEN et al.			
AH	6,957,083	10/2005	IKEDA et al.			
AH	6,967,280	11/2005	BOATWRIGHT et al.			
AH	7,006,854	2/2006	CHOI, Yong-Chai			

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AH	2004/0077385	4/2004	MAKINO et al.			
AH	2005/0141187	6/2005	SHIMIZU, Masahito			
AH	2006/0110608	5/2006	AZUMI et al.			

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PUBLICATION NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes	Translation No
AH	1998-0057623	10/1998	Korea (Eng. Abstract and Full Korean Text)			X	
AH	2001-0027039	4/2001	Korea (Eng. Abstract and Full Korean Text)			X	
AH	2002-0066806	8/2002	Korea (Eng. Abstract and Full Korean Text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

AH	Korean Office Action dated October 16, 2004
AH	Korean Office Action dated October 21, 2004
AH	Korean Office Action dated October 27, 2004

EXAMINER	DATE CONSIDERED
/Adeel Haroon/	01/23/2007

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes	Translation No
AH	JP 09-283950	10/1997	JAPAN (English Abstract and Japanese Full Text)			X	
AH	CN 2414554Y	1/2001	CHINA (English Abstract and Chinese Full Text)			X	
AH	CN 2447830Y	9/2001	CHINA (English Abstract and Chinese Full Text)			X	
AH	CN 1375976	10/2002	CHINA (English Abstract and Chinese Full Text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

AH	Chinese Office Action dated December 10, 2004

EXAMINER	/Adeel Haroon/	DATE CONSIDERED	01/23/2007

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